JDT

LOW SKEW, DUAL, 1-TO-3 DIFFERENTIAL-TO-LVDS FANOUT BUFFER

ICS854S013

General Description

The ICS854S013 is a low skew, high performance Dual 1-to-3 Differential-to-LVDS Fanout Buffer and a member of the HiPerClockS™ family of High Performance Clock Solutions from IDT. The PCLKx, nPCLKx pairs can accept most standard differential

input levels. The ICS854S013 is characterized to operate from a 3.3V power supply. Guaranteed output and bank skew characteristics make the ICS854S013 ideal for those clock distribution applications demanding well defined performance and repeatability.

Features

- **•** Two differential LVDS output banks
- **•** Two differential clock input pairs
- **•** PCLKx, nPCLKx pairs can accept the following differential input levels: LVPECL, LVDS, CML, SSTL
- **•** Maximum output frequency: >3GHz
- **•** Translates any single ended input signal to LVDS levels with resistor bias on nPCLKx input
- **•** Output skew: <25ps (typical)
- **•** Bank skew: <50ps (typical)
- **•** Propagation delay: TBD
- **•** Additive phase jitter, RMS: 0.15ps (typical)
- **•** Full 3.3V power supply
- **•** 0°C to 70°C ambient operating temperature
- **•** Available in both standard (RoHS 5) and lead-free (RoHS 6) packages

Pin Assignment

ICS854S013 20-Lead TSSOP 6.5mm x 4.4mm x 0.925mm package body

G Package Top View

The Preliminary Information presented herein represents a product in pre-production. The noted characteristics are based on initial product characterization and/or qualification. Integrated Device Technology, Incorporated (IDT) reserves the right to change any circuitry or specifications without notice.

Block Diagram

Table 1. Pin Descriptions

NOTE: *Pullup and Pulldown* refer to internal input resistors. See Table 2, *Pin Characteristics,* for typical values.

Table 2. Pin Characteristics

Table 3. Clock Input Function Table

NOTE 1: Please refer to the Application Information Section, *Wiring the Differential Input to Accept Single-ended Levels.*

Absolute Maximum Ratings

NOTE: Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the *DC Characteristics or AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

DC Electrical Characteristics

Table 4A. LVDS Power Supply DC Characteristics, $V_{DD} = 3.3V \pm 5\%$ **,** $T_A = 0^{\circ}C$ **to 70°C**

Table 4B. LVPECL Differential DC Characteristics, $V_{DD} = 3.3V \pm 5\%$, $T_A = 0^{\circ}C$ to 70°C

NOTE 1: V_{IL} should not be less than -0.3V.

NOTE 2: Common mode input voltage is defined as V_{IH} .

Table 4C. LVDS DC Characteristics, $V_{DD} = 3.3V \pm 5\%$, $T_A = 0^{\circ}C$ to 70°C

Table 5. AC Characteristics, $V_{DD} = 3.3V \pm 5\%$, $T_A = 0^\circ \text{C}$ to 70 $^\circ \text{C}$

All parameters measured at 500MHz unless noted otherwise.

NOTE 1: Measured from the differential input crossing point to the differential output crossing point.

NOTE 2: Defined as skew between outputs at the same supply voltage and with equal load conditions. Measured from the output differential cross points.

NOTE 3: Defined as skew within a bank of outputs at the same voltage and with equal load conditions.

NOTE 4: This parameter is defined in accordance with JEDEC Standard 65.

Additive Phase Jitter

0

The spectral purity in a band at a specific offset from the fundamental compared to the power of the fundamental is called the *dBc Phase Noise.* This value is normally expressed using a Phase noise plot and is most often the specified plot in many applications. Phase noise is defined as the ratio of the noise power present in a 1Hz band at a specified offset from the fundamental frequency to the power value of the fundamental. This ratio is expressed in decibels (dBm) or a ratio of the power in the 1Hz band

to the power in the fundamental. When the required offset is specified, the phase noise is called a *dBc* value, which simply means dBm at a specified offset from the fundamental. By investigating jitter in the frequency domain, we get a better understanding of its effects on the desired application over the entire time record of the signal. It is mathematically possible to calculate an expected bit error rate given a phase noise plot.

As with most timing specifications, phase noise measurements has issues relating to the limitations of the equipment. Often the noise floor of the equipment is higher than the noise floor of the

device. This is illustrated above. The device meets the noise floor of what is shown, but can actually be lower. The phase noise is dependent on the input source and measurement equipment.

Parameter Measurement Information

3.3V LVDS Output Load AC Test Circuit

Differential Input Level

Output Skew

Output Duty Cycle/Pulse Width/Period

Bank Skew

Propagation Delay

Parameter Measurement Information, continued

Offset Voltage Setup

Differential Output Voltage Setup

Recommendations for Unused Input and Output Pins

Inputs:

PCLK/nPCLK Inputs

For applications not requiring the use of a differential input, both the PCLK and nPCLK pins can be left floating. Though not required, but for additional protection, a 1kΩ resistor can be tied from PCLK to ground.

Outputs:

LVDS Outputs

All unused LVDS output pairs can be either left floating or terminated with 100 Ω across. If they are left floating, there should be no trace attached.

Wiring the Differential Input to Accept Single-Ended Levels

Figure 1 shows how the differential input can be wired to accept single-ended levels. The reference voltage V_REF = $V_{DD}/2$ is generated by the bias resistors R1, R2 and C1. This bias circuit should be located as close as possible to the input pin. The ratio of R1 and R2 might need to be adjusted to position the V_REF in the center of the input voltage swing. For example, if the input clock swing is only 2.5V and $V_{DD} = 3.3V$, V_REF should be 1.25V and $R2/R1 = 0.609$.

Figure 1. Single-Ended Signal Driving Differential Input

LVPECL Clock Input Interface

The PCLK /nPCLK accepts LVPECL, CML, SSTL and other differential signals. Both signals must meet the V_{PP} and V_{CMB} input requirements. *Figures 2A to 2F* show interface examples for the HiPerClockS PCLK/nPCLK input driven by the most common

Figure 2A. HiPerClockS PCLK/nPCLK Input Driven by an Open Collector CML Driver

Figure 2C. HiPerClockS PCLK/nPCLK Input Driven by a 3.3V LVPECL Driver

Figure 2E. HiPerClockS PCLK/nPCLK Input Driven by an SSTL Driver

driver types. The input interfaces suggested here are examples only. If the driver is from another vendor, use their termination recommendation. Please consult with the vendor of the driver component to confirm the driver termination requirements.

Figure 2B. HiPerClockS PCLK/nPCLK Input Driven by a Built-In Pullup CML Driver

Figure 2D. HiPerClockS PCLK/nPCLK Input Driven by a 3.3V LVPECL Driver with AC Couple

Figure 2F. HiPerClockS PCLK/nPCLK Input Driven by a 3.3V LVDS Driver

3.3V LVDS Driver Termination

A general LVDS interface is shown in *Figure 3.* In a 100Ω differential transmission line environment, LVDS drivers require a matched load termination of 100Ω across near the receiver input.

For a multiple LVDS outputs buffer, if only partial outputs are used, it is recommended to terminate the unused outputs.

Figure 3. Typical LVDS Driver Termination

Power Considerations

This section provides information on power dissipation and junction temperature for the ICS854S013. Equations and example calculations are also provided.

1. Power Dissipation.

The total power dissipation for the ICS854S013 is the sum of the core power plus the power dissipated in the load(s). The following is the power dissipation for $V_{DD} = 3.3V + 5\% = 3.465V$, which gives worst case results.

Power (core) $_{MAX}$ = V_{DD} $_{MAX}$ $*$ I_{DD} $_{MAX}$ = 3.465V $*$ 135mA = 467.77mW

2. Junction Temperature.

Junction temperature, Tj, is the temperature at the junction of the bond wire and bond pad and directly affects the reliability of the device. The maximum recommended junction temperature for HiPerClockS devices is 125°C.

The equation for Tj is as follows: Tj = θ_{JA} * Pd_total + T_A

Tj = Junction Temperature

 θ_{JA} = Junction-to-Ambient Thermal Resistance

Pd total = Total Device Power Dissipation (example calculation is in section 1 above)

 T_A = Ambient Temperature

In order to calculate junction temperature, the appropriate junction-to-ambient thermal resistance θ_{JA} must be used. Assuming no air flow and a multi-layer board, the appropriate value is 87.2°C/W per Table 6 below.

Therefore, Tj for an ambient temperature of 70°C with all outputs switching is:

 70° C + 0.468W * 87.2°C/W = 110.8°C. This is below the limit of 125°C.

This calculation is only an example. Tj will obviously vary depending on the number of loaded outputs, supply voltage, air flow and the type of board (single layer or multi-layer).

Table 6. Thermal Resistance θJA **for 20 Lead TSSOP, Forced Convection**

Reliability Information

Table 7. θ**JA vs. Air Flow Table for a 20 Lead TSSOP**

Transistor Count

The transistor count for ICS854S013 is: 363

Package Outline and Package Dimensions

Package Outline - G Suffix for 20 Lead TSSOP Table 8 Package Dimensions

Reference Document: JEDEC Publication 95, MO-153

Ordering Information

Table 9. Ordering Information

NOTE: Parts that are ordered with an "LF" suffix to the part number are the Pb-Free configuration and are RoHS compliant.

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